

Notice of References Cited

Application/Control No.

10/528,400

Applicant(s)/Patent Under
Reexamination
SIEKE ET AL.

Examiner

Edward F. Landrum

Art Unit

3724

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,848,471	12-1998	Freeland, Jay	30/280
*	B	US-4,693,004	09-1987	Plana, Salvio	30/265
*	C	US-5,044,081	09-1991	Nguyen, Tan D.	30/294
*	D	US-4,604,802	08-1986	Samuelsson, Soren	30/124
*	E	US-2001/0034919	11-2001	Faggiotto, Elberino	15/236.06
*	F	US-5,809,652	09-1998	Ducret, Lucien C.	30/90.7
*	G	US-5,381,601	01-1995	Danter et al.	30/90.1
*	H	US-2,013,893	09-1935	Matthews, Ross R.	83/455
*	I	US-6,581,291	06-2003	Tarpill et al.	30/90.4
*	J	US-3,611,571	10-1971	Belling, William F.	30/280
*	K	US-3,886,657	06-1975	Fabian, Ralf	30/294
*	L	US-5,285,577	02-1994	Carney et al.	30/294
*	M	US-5,027,515	07-1991	Murdock, Clifford R.	30/292

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE3510738	10-1986	Germany	Meitzel, Horst	B60S 5/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.